

# Hit position error estimation for the CBM Silicon Tracking System

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## Introduction: Silicon Tracking System

Main STS task is to reconstruct tracks with:

- ▶ high momentum resolution ( $\Delta p/p \approx 1.5\%$  for  $p > 1$  GeV);
- ▶ high track reconstruction efficiency ( $> 96\%$  for  $p > 1$  GeV).

This leads to the requirements:

- ▶ **high spatial resolution**  $\Rightarrow$  high granularity;
- ▶ low material budget.

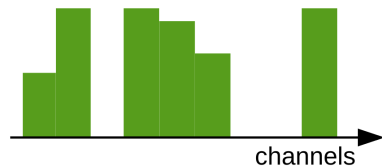
Design decision: 8 stations, double-sided Si sensors in 1 T magnetic field, r/o electronics outside of the acceptance connected to the sensors with thin microcables.

**Spatial resolution** are limited with:

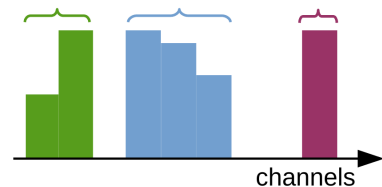
- ▶ multiple scattering;
- ▶ **intrinsic detector resolution.**

## Cluster finding

Fired channels:



Clusters:



- Neighbouring digis (which presumably originate from the same incident particle) makes a cluster;
- Estimate cluster centre using measured charges  $q_i$ .

## Cluster position finding algorithm

### Centre-Of-Gravity algorithm (COG):

$$x_{\text{rec}} = \frac{\sum x_i q_i}{\sum q_i}$$

$x_i$  – the coordinate of  $i$ th strip,  
 $q_i$  – its charge,  
 $i = 1..n$  – the strip index in the  $n$ -strip cluster.

COG is biased:  $\langle x_{\text{true}} - x_{\text{rec}} \rangle \equiv \langle \Delta x \rangle \neq 0$  for  $n \geq 2$  at fixed  $q_2/q_1$ .

### An unbiased algorithm:

2-strip clusters:

$$x_{\text{rec}} = 0.5 (x_1 + x_2) + \frac{p}{3} \frac{q_2 - q_1}{\max(q_1, q_2)}, \quad p - \text{strip pitch};$$

$n$ -strip clusters (Analog head-tail algorithm<sup>1</sup>):

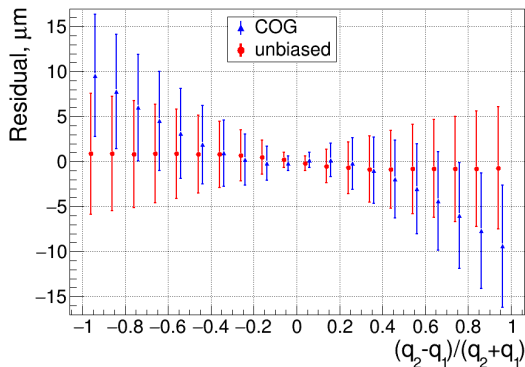
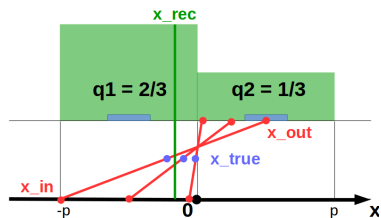
$$x_{\text{rec}} = 0.5 (x_1 + x_n) + \frac{p}{2} \frac{\min(q_n, q) - \min(q_1, q)}{q}, \quad q = \frac{1}{n-2} \sum_{i=2}^{n-1} q_i.$$

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<sup>1</sup>R. Turchetta, "Spatial resolution of silicon microstrip detectors", 1993

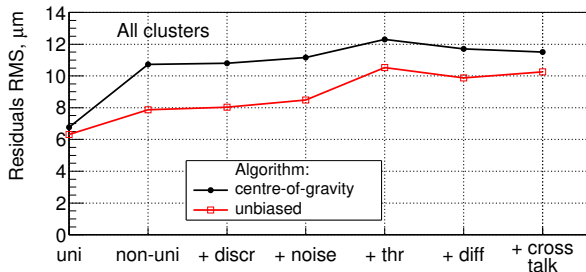
# COG vs Unbiased cluster position finding algorithm.

## 2-strip clusters example



Ideal detector model & uniform energy loss.  
 Error bars: RMS of the residual distribution.  
 $q_{1,2}$  – measured charges on the strips.

## Comparison of residuals: COG vs Unbiased algorithms



*1000 minimum bias Au+Au events at 10 AGeV are simulated with the realistic STS geometry.*

- ▶ The unbiased algorithm is faster and simplifies the hit position error estimation.

## Hit position error: introduction and motivation

**Importance:** A reliable estimate of the hit position error  $\Rightarrow$   
get proper track  $\chi^2 \Rightarrow$   
discard ghost track candidates  $\Rightarrow$   
improve the signal/background and keep the efficiency high.

**Method:** Calculations from basic principles and independent of:  
simulated residuals;  
measured spatial resolution.

**Verification:** hit pull distribution: shape and width;  
track  $\chi^2$  distribution: mean value.

## Hit position error: basic ideas

$$\sigma^2 = \sigma_{\text{alg}}^2 + \sum_i \left( \frac{\partial x_{\text{rec}}}{\partial q_i} \right)^2 \sum_{\text{sources}} \sigma_j^2,$$

$\sigma_{\text{alg}}$  – an error of the cluster position finding algorithm;

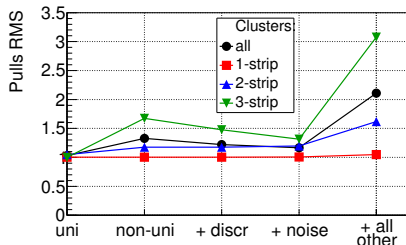
$\sigma_j$  – errors of the charge registration at one strip, among them already included:

- ▶  $\sigma_{\text{noise}} =$  Equivalent Noise Charge;
- ▶  $\sigma_{\text{discr}} = \frac{\text{dynamic range}}{\sqrt{12} \text{ number of ADC}};$
- ▶  $\sigma_{\text{non-uni}}$  is estimated assuming:
  - ▶ registered charge corresponds to the most probable value of the energy loss;
  - ▶ incident particle is ultrarelativistic ( $\beta\gamma \gtrsim 100$ ).
- ▶  $\sigma_{\text{diff}}$  is negligible in comparison with other effects.

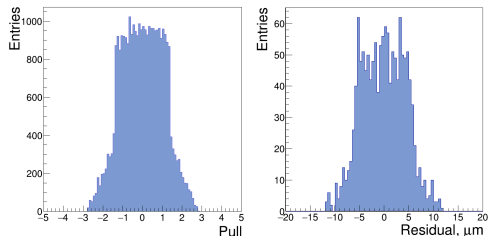


## Verification: hit pull distribution

### Width



### Shape

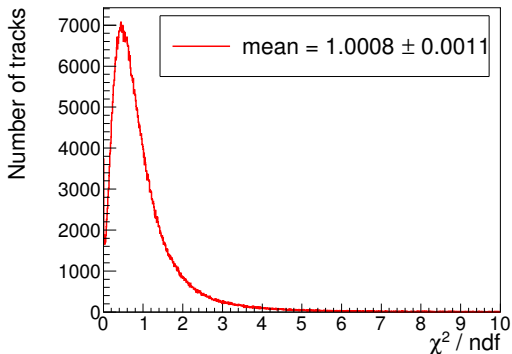


1000 mbias events Au+Au @ 10 AGeV

Ideal detector, 2-strip clusters,  
residuals at fixed:  $\frac{|q_2 - q_1|}{\max(q_1, q_2)}$ .

- ▶  $\text{pull} = \frac{\text{residual}}{\text{error}}$ ;
- ▶ pull distribution width must be  $\approx 1$ ;
- ▶ pull distribution shape must reproduce residual shape.

## Verification: track $\chi^2$ distribution



*10 000 minimum bias events Au+Au @ 10 AGeV*

- ▶  $\chi^2 / \text{ndf}$  distribution for tracks: mean value must be  $\approx 1$ .

## Summary

For the Silicon Tracking System of the CBM experiment:

- ▶ Two **cluster position finding algorithms** were implemented: Centre-Of-Gravity and the unbiased. The last:
  - ▶ gives similar residuals as the Centre-Of-Gravity algorithm;
  - ▶ simplifies position error estimation.
- ▶ Developed method of the **hit position error estimation** yields correct errors, that was verified with:
  - ▶ hit pulls distribution (width and shape);
  - ▶ track  $\chi^2/\text{ndf}$  distribution.

## Summary

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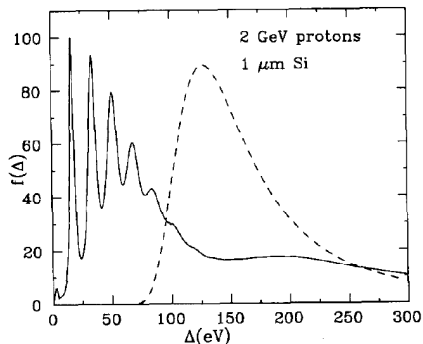
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  - ▶ hit pulls distribution (width and shape);
  - ▶ track  $\chi^2/\text{ndf}$  distribution.

Thank you for your attention!

## Detector response model:

- ▶ non-uniform energy loss in sensor: *divide a track into small steps and simulate energy losses in each of them using Urban model<sup>1</sup>*;
- ▶ drift of created charge carriers in planar electric field
- ▶ movement of e-h pairs in magnetic field (Lorentz shift)
- ▶ diffusion
- ▶ cross-talk due to interstrip capacitance
- ▶ modeling of the read-out chip

<sup>1</sup> K. Lassila-Perini and L. Urbán (1995)

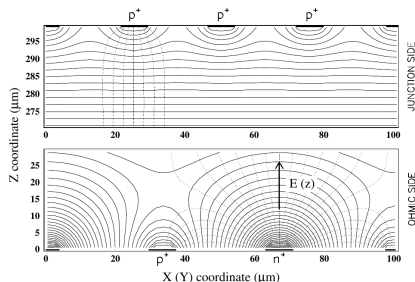


Energy losses of 2 GeV protons in 1  $\mu\text{m}$  of Si (solid line)<sup>2</sup>.

<sup>2</sup> H. Bichsel (1990)

## Detector response model:

- ▶ non-uniform energy loss in sensor
- ▶ drift of created charge carriers in planar electric field:  
*non-uniformity of the electric field is negligible in 90% of the volume;*
- ▶ movement of e-h pairs in magnetic field (Lorentz shift)
- ▶ diffusion
- ▶ cross-talk due to interstrip capacitance
- ▶ modeling of the read-out chip

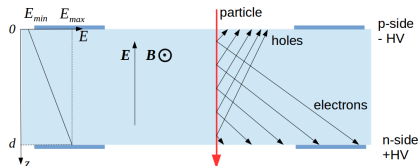


Calculated electric field for sensors with strip pitch  $25.5\ \mu\text{m}$  on the p-side and  $66.5\ \mu\text{m}$  on the n-side<sup>1</sup>.

<sup>1</sup> S. Straulino et al. (2006)

## Detector response model:

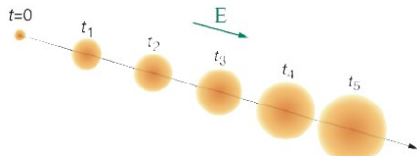
- ▶ non-uniform energy loss in sensor
- ▶ drift of created charge carriers in planar electric field
- ▶ movement of e-h pairs in magnetic field (Lorentz shift):  
*taking into account the fact that Lorentz shift depends on the mobility, which depends on the electric field, which depends on the z-coordinate of charge carrier;*
- ▶ diffusion
- ▶ cross-talk due to interstrip capacitance
- ▶ modeling of the read-out chip



*Lorentz shift for electrons and holes in Si sensor.*

## Detector response model:

- ▶ non-uniform energy loss in sensor
- ▶ drift of created charge carriers in planar electric field
- ▶ movement of e-h pairs in magnetic field (Lorentz shift)
- ▶ diffusion:
  - integration time is bigger than the drift time: estimate the increase of the charge carrier cloud during the whole drift time using Gaussian law;*
- ▶ cross-talk due to interstrip capacitance
- ▶ modeling of the read-out chip



*Increasing of charge cloud in time.*

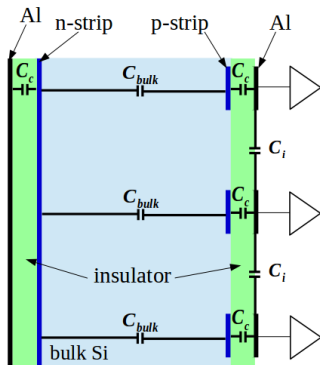


## Detector response model:

- ▶ non-uniform energy loss in sensor
- ▶ drift of created charge carriers in planar electric field
- ▶ movement of e-h pairs in magnetic field (Lorentz shift)
- ▶ diffusion
- ▶ cross-talk due to interstrip capacitance:

$$Q_{\text{neib strip}} = \frac{Q_{\text{strip}} C_i}{C_c + C_i};$$

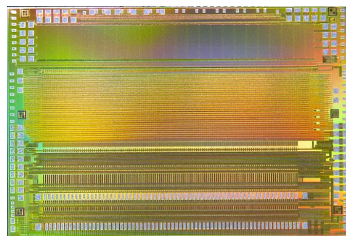
- ▶ modeling of the read-out chip



*Simplified double-sided silicon microstrip detector layout.*

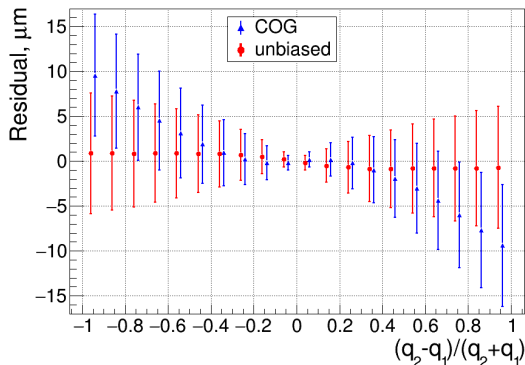
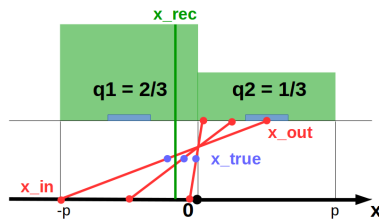
## Detector response model:

- ▶ non-uniform energy loss in sensor
- ▶ drift of created charge carriers in planar electric field
- ▶ movement of e-h pairs in magnetic field (Lorentz shift)
- ▶ diffusion
- ▶ cross-talk due to interstrip capacitance
- ▶ modeling of the read-out chip:
  - ▶ *noise: + Gaussian noise to the signal in fired strip;*
  - ▶ *threshold;*
  - ▶ *digitization of analog signal;*
  - ▶ *time resolution;*
  - ▶ *dead time.*



*STS-XYTER read-out chip for the CBM Silicon Tracking System.*

## Residuals comparison for 2 CPFAs: 2-strip clusters



Ideal detector model & uniform energy loss.  
 Error bars: RMS of the residual distribution.  
 $q_{1,2}$  – measured charges on the strips.

# Unbiased cluster position finding algorithm (CPFA), n-strip clusters

formula for **uniform** energy loss:

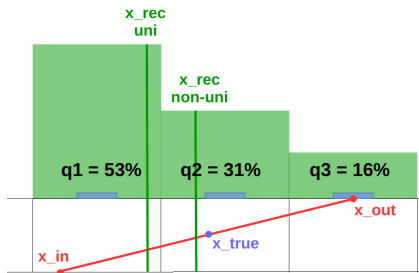
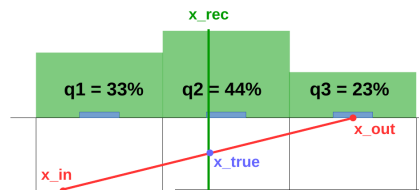
$$x_{\text{rec}} = 0.5(x_1 + x_n) + \frac{p}{2} \frac{q_n - q_1}{q},$$

$$q = \frac{1}{n-2} \sum_{i=2}^{n-1} q_i;$$

formula for **non-uniform** energy loss (head-tail algorithm<sup>1</sup>):

$$x_{\text{rec}} = 0.5(x_1 + x_n) + \frac{p}{2} \frac{\min(q_n, q) - \min(q_1, q)}{q},$$

<sup>1</sup> R. Turchetta, "Spatial resolution of silicon microstrip detectors", 1993



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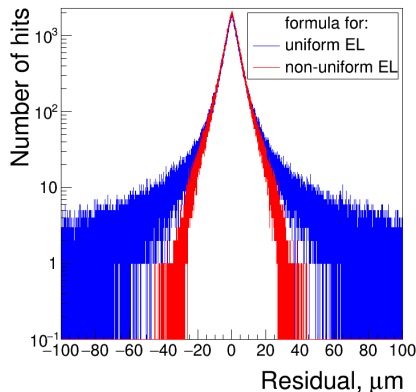
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<sup>1</sup> R. Turchetta, "Spatial resolution of silicon microstrip detectors", 1993

Residuals for 3-strip clusters



## Estimation of hit position error

$$\text{Hit position error: } \sigma^2 = \sigma_{\text{alg}}^2 + \sum_i \left( \frac{\partial x_{\text{rec}}}{\partial q_i} \right)^2 \sum_{\text{sources}} \sigma_j^2,$$

$\sigma_{\text{alg}}$  – an error of the unbiased CPFA:

$$\sigma_1 = \frac{p}{\sqrt{24}}, \quad \sigma_2 = \frac{p}{\sqrt{72}} \frac{|q_2 - q_1|}{\max(q_1, q_2)}, \quad \sigma_{n>2} = 0.$$

$\sigma_j$  – errors of the charge registration at one strip, among them already included:

- ▶  $\sigma_{\text{noise}}$  = Equivalent Noise Charge;
- ▶  $\sigma_{\text{discr}} = \frac{\text{dynamic range}}{\sqrt{12} \text{ number of ADC}}$ ;
- ▶  $\sigma_{\text{non-uni}}$  is estimated assuming:
  - ▶ registered charge corresponds to the most probable value of the energy loss;
  - ▶ incident particle is ultrarelativistic ( $\beta\gamma \gtrsim 100$ ).
- ▶  $\sigma_{\text{diff}}$  is negligible in comparison with other effects.

## Error due to non-uniform energy loss

The contribution from the non-uniformity of energy loss is more difficult to take into account because the actual energy deposit along the track is not known. The following approximations allow a straightforward solution:

- ▶ the registered charge corresponds to the most probable value (MPV) of energy loss;
- ▶ the incident particle is ultrarelativistic ( $\beta\gamma \gtrsim 100$ ).

The second assumption is very strong but it uniquely relates the MPV and the distribution width (Particle Data Group)

$$MPV = \xi[\text{eV}] \times (\ln(1.057 \times 10^6 \xi[\text{eV}]) + 0.2).$$

Solving this with respect to  $\xi$  gives the estimate for the FWHM (S. Merolli, D. Passeri and L. Servoli, Journal of Instrumentation, Volume 6, 2011)

$$\sigma_{\text{non}} = w/2 = 4.018\xi/2.$$

# 1-strip clusters: why not $\sigma_{method} = p/\sqrt{12}$ ?

In general, for **all** track inclinations:

$$\blacktriangleright N = \int_{x_{in}} \int_{x_{out}} P_1(x_{in}, x_{out}) dx_{in} dx_{out} = p^2;$$

$$\blacktriangleright \sigma^2 = \frac{1}{N} \int_{x_{in}} \int_{x_{out}} P_1(x_{in}, x_{out}) dx_{in} dx_{out} \Delta x^2 = \frac{p^2}{24}.$$

Particullary, for **perpendicular** tracks:  $x_{in} = x_{out}$

$$\blacktriangleright N = \int_{x_{in}} P_1(x_{in}, x_{out}) dx_{in} = p;$$

$$\blacktriangleright \sigma^2 = \frac{1}{N} \int_{x_{in}} P_1(x_{in}, x_{out}) dx_{in} \Delta x^2 = \frac{p^2}{12}$$